Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/811,504	HYEON ET AL.	
Examiner B05	Art Unit	

SEARCHED				
Class	Subclass	Date	Examiner	
423	299,351, 509,561.1, 592.1,622	10/5,6,	AEH	
977	DIG. 1	2005	AEH	
Mpl	ated	7-06	2 Ms	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
eDAN inventor search	10/5/2005	AEH		
EAST searches of DERWENT; USPAT/USPGPUB; &/or EPO/JPO/IBM_TDB databases (see attached strategy)	14,16	AEH		
reviewed related copending appln. 10/641,394 (1 common inventor, same assignee)	10/14,16	AEH		
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